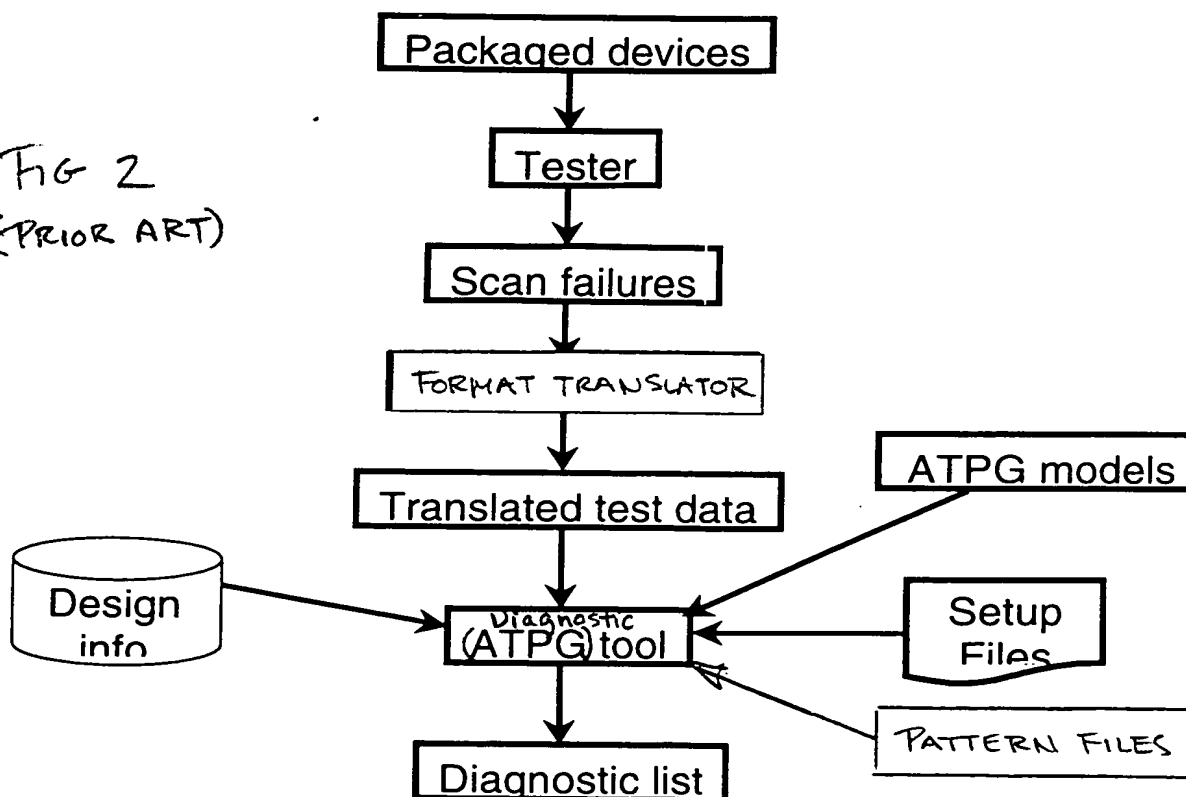
FIG 1
(PRIOR ART)FIG 2
(PRIOR ART)

09192164-111398

DeviceID = DEMO1D
 LotID = TESTLOT01
 WaferID = 01
 DIE = -4,0
 datalog.scan.10 diagnosis summary, #failing_patterns=9 #defects=2
 #unexplained_fails=2
 unexplained patterns = 212 250

 fault candidates for defect 1, #failing_patterns_explained=5

Warning: Fault candidates will cause passing patterns to fail.

failing patterns explained = 322 706 738 770

type code pin_pathname

 1 DS /XTIO_0/XTTLI8_1612/N2_23
 1 DS /PI9

diagnosis CPU time = .68 sec

FIG 3 (PRIOR ART)

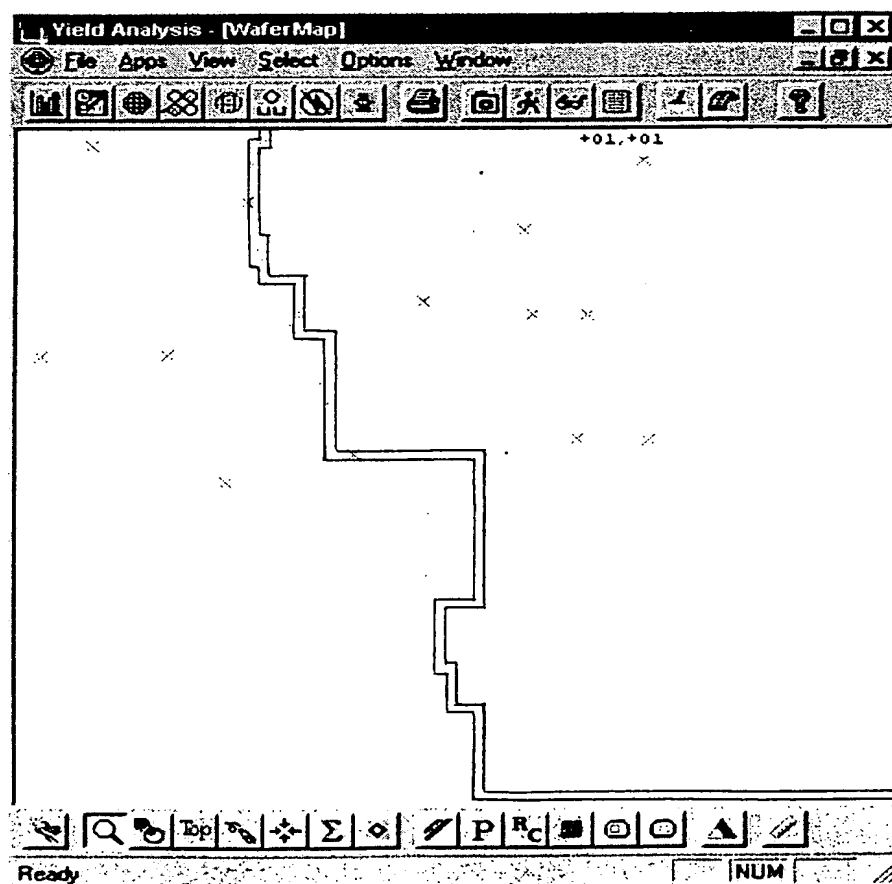


FIG 7

09192154-111398

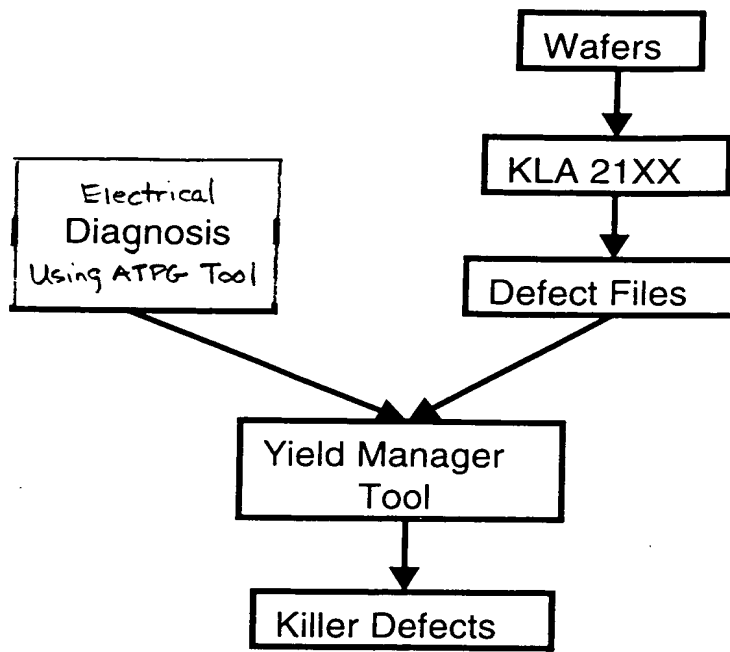


FIG. 5

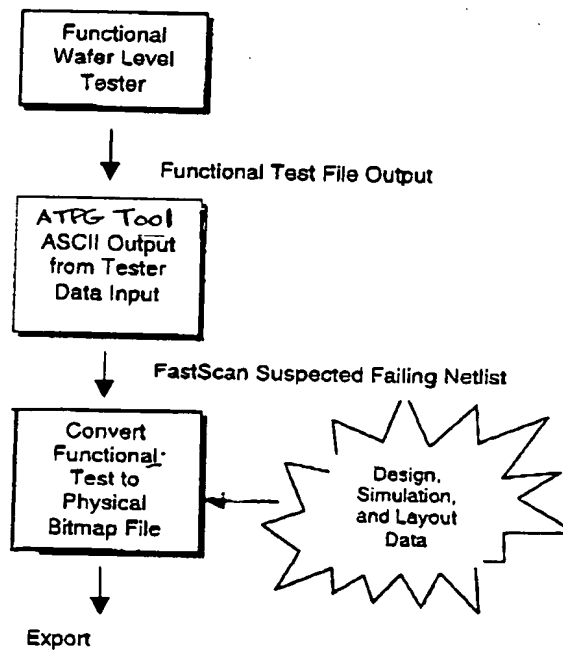
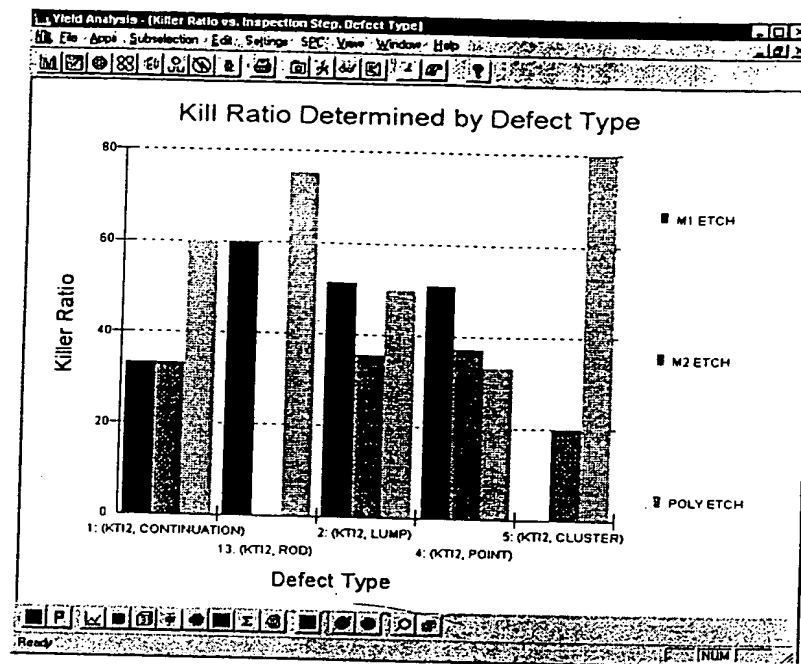


FIG. 6

FIG 8



Bitmap Fail Intensity Stackmap Vs Layout X, Y Coordinates

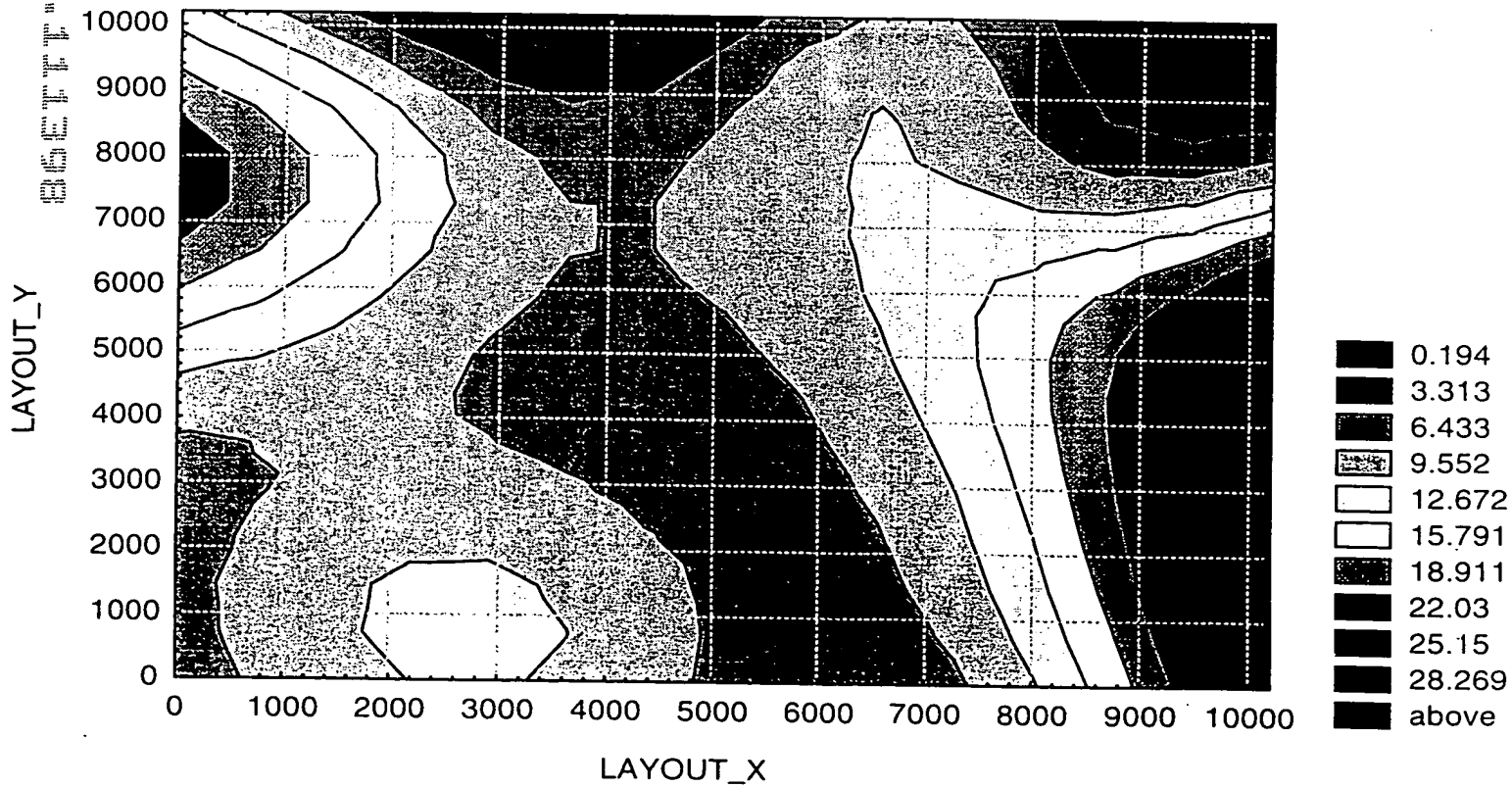


FIG 9

09192164-1139B
B6EFT-1926T60

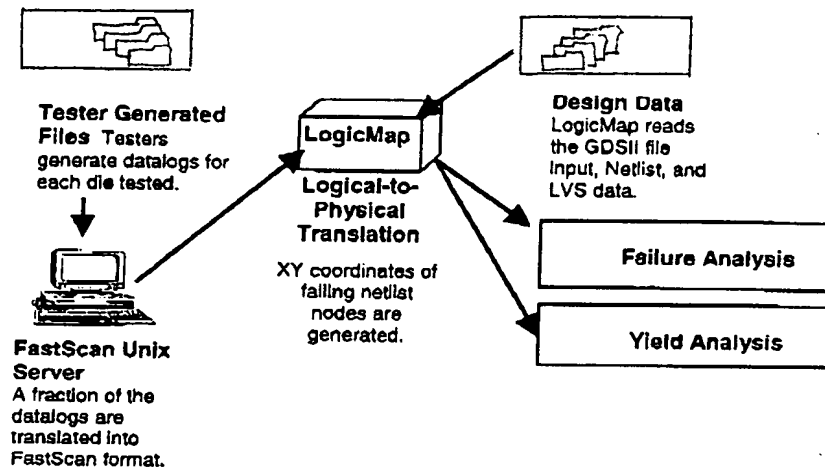
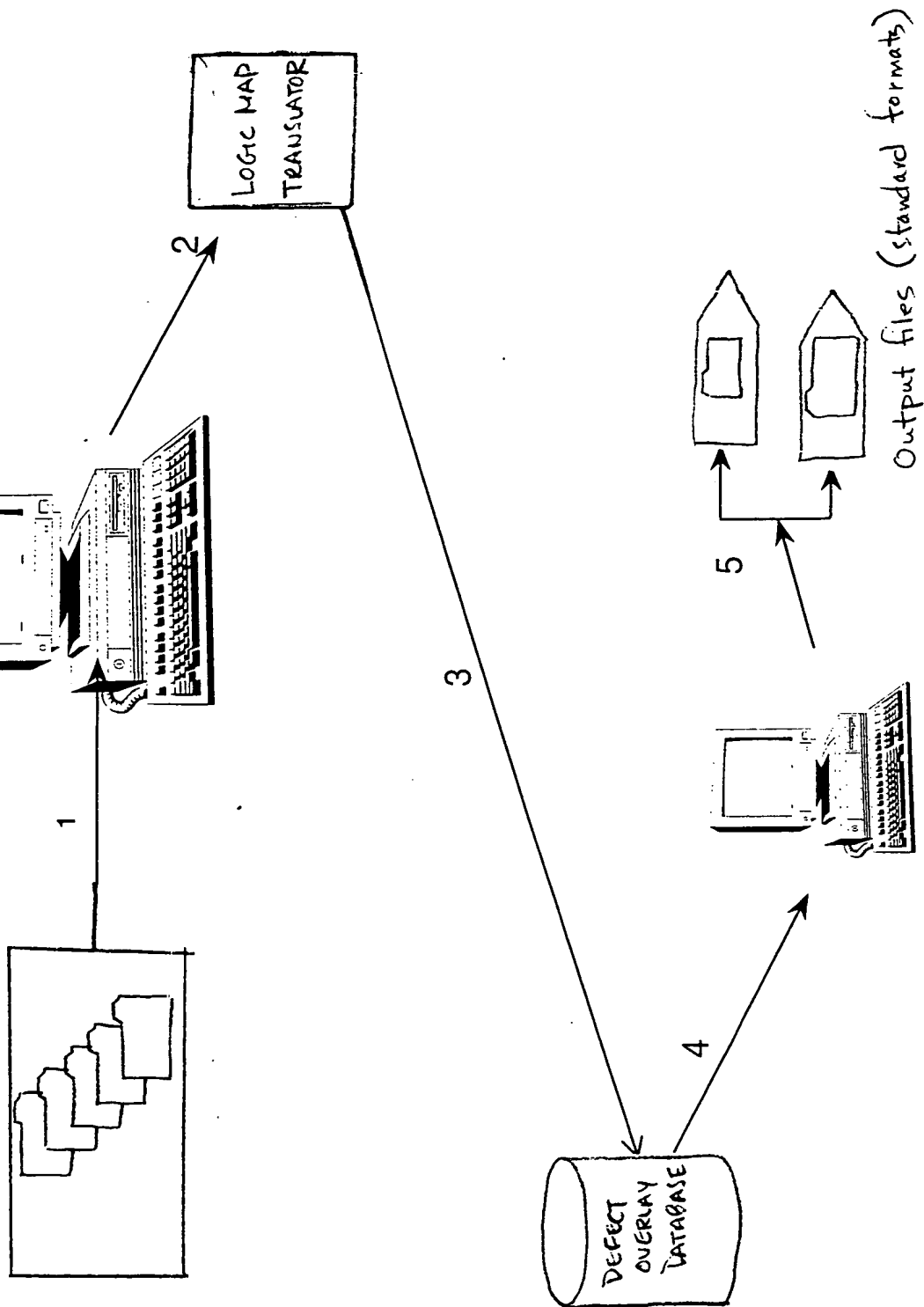


Fig 10

85E1T 4926T60

Tester Generated Files



PC Client
viewing/analysis

FIG-11

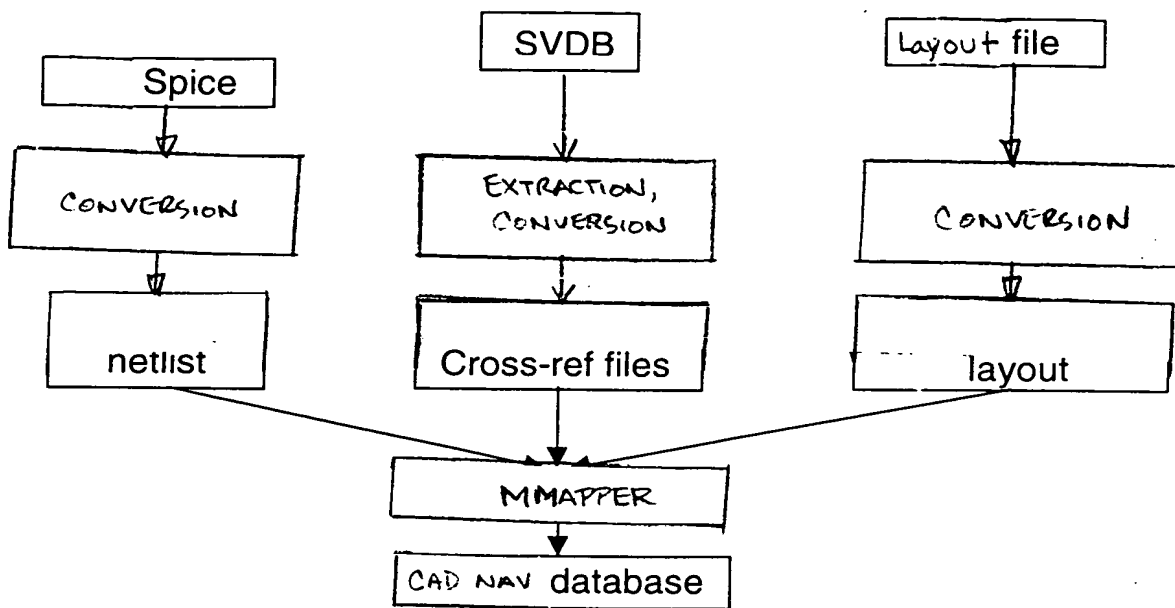


FIG 4 (PRIOR ART)

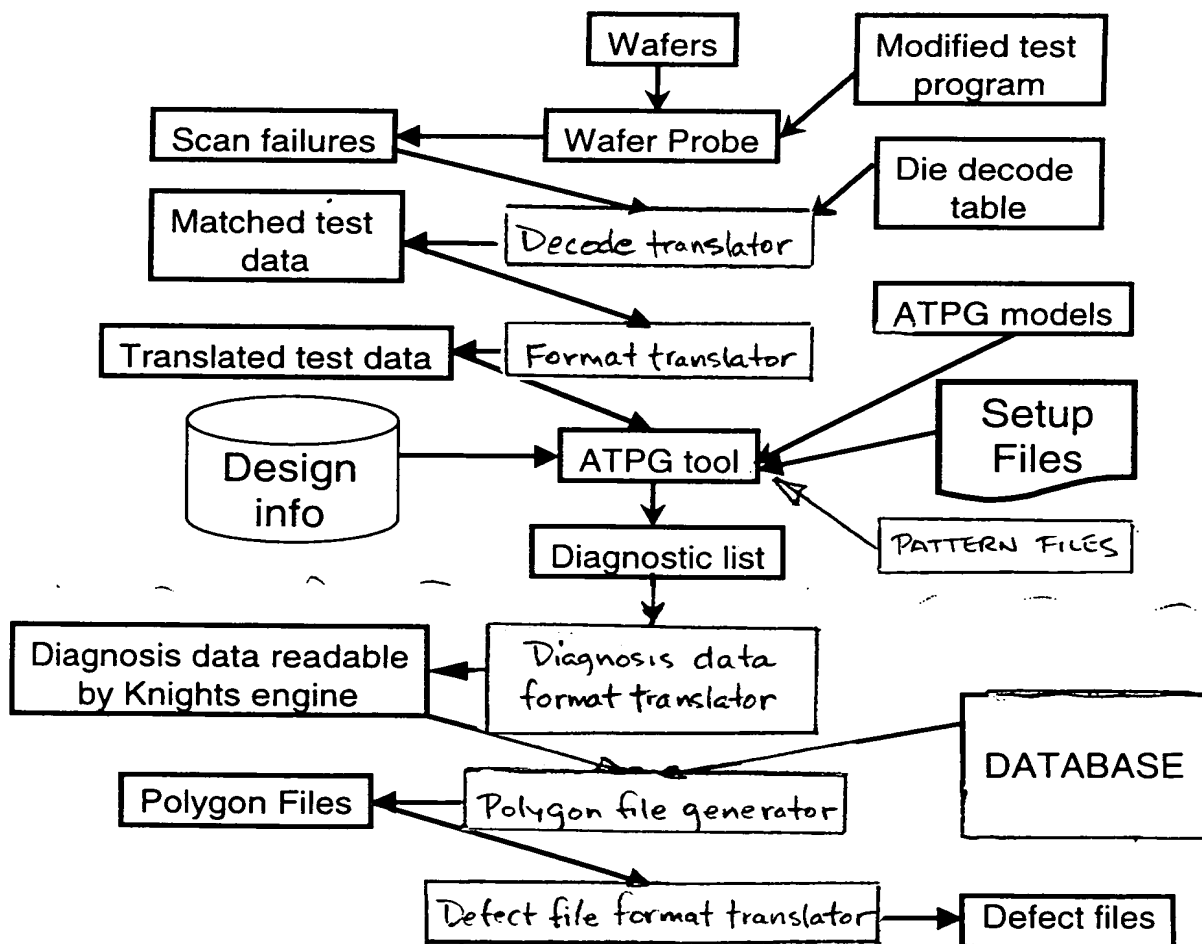


FIG 12